## **Notice of References Cited**

Application/Control No. 10/528,641	Reexamination	Applicant(s)/Patent Under Reexamination SAHASHI, NOZOMU	
Examiner	Art Unit		
Bruk A. Gebremichael	3709	Page 1 of 1	

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,029,043 A	02-2000	Ho et al.	434/350
*	В	US-2002/0002477 A1	01-2002	Fox et al.	705/7
*	С	US-2003/0023444 A1	01-2003	ST. JOHN, VICKI	704/270.1
*	D	US-2003/0009339 A1	01-2003	Yuen et al.	704/260
*	E	US-2003/0039380 A1	02-2003	Sukegawa et al.	382/118
*	F	US-2003/0133599 A1	07-2003	Tian et al.	382/118
*	G	US-2004/0122790 A1	06-2004	Walker et al.	707/001
*	Н	US-2004/0205818 A1	10-2004	Saruhashi et al.	725/061
*	1	US-2005/0033573 A1	02-2005	Hong et al.	704/250
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO-02/103597 A1	12-2002	WIPO	Jung, Soon-Won	G06F 17/60
	0					
	Р					
	a					
	R					
	S					
	T					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	-				
	. <b>V</b>					
	w					
	×					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.